



Title: IMPROVING SEM INSPECTION AND ANALYSIS OF PATTERNED PHOTORESIST FEATURES
Inventor(s): Uzodinma Okoroanyanwu et al.
Appl. NO.: 09 / 820, 143

1 / 4

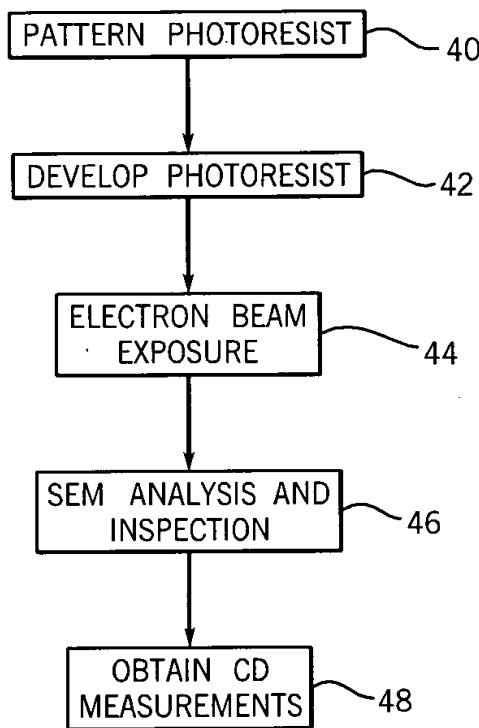


FIG. 1



2 / 4

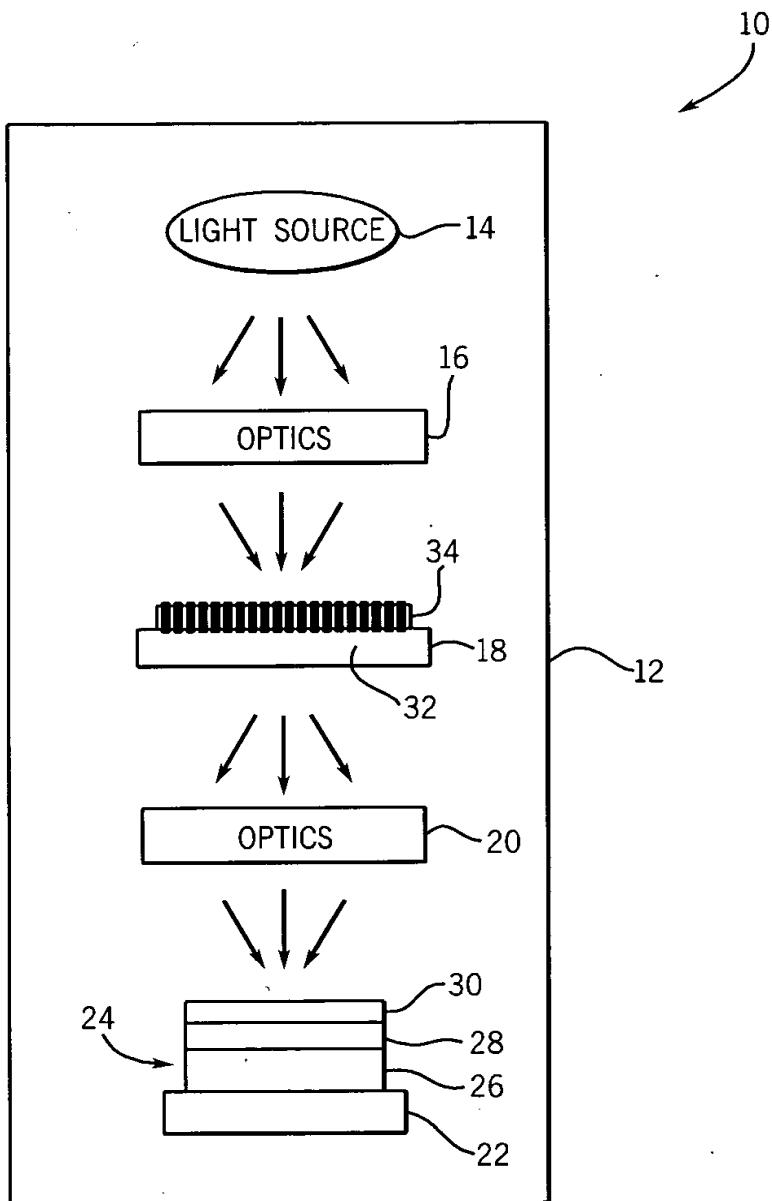


FIG. 2



3 / 4

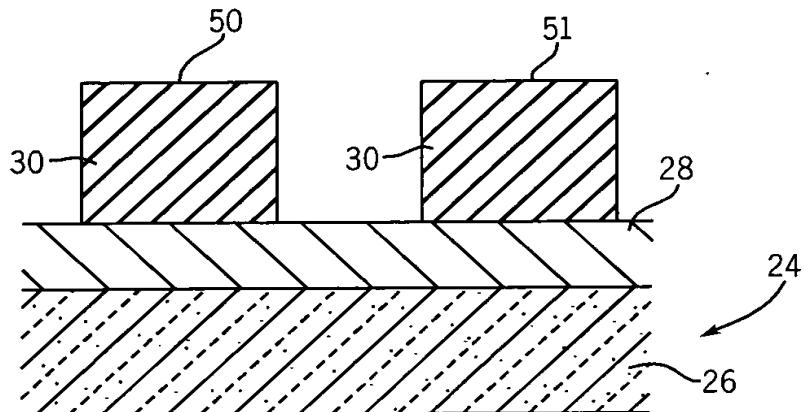


FIG. 3

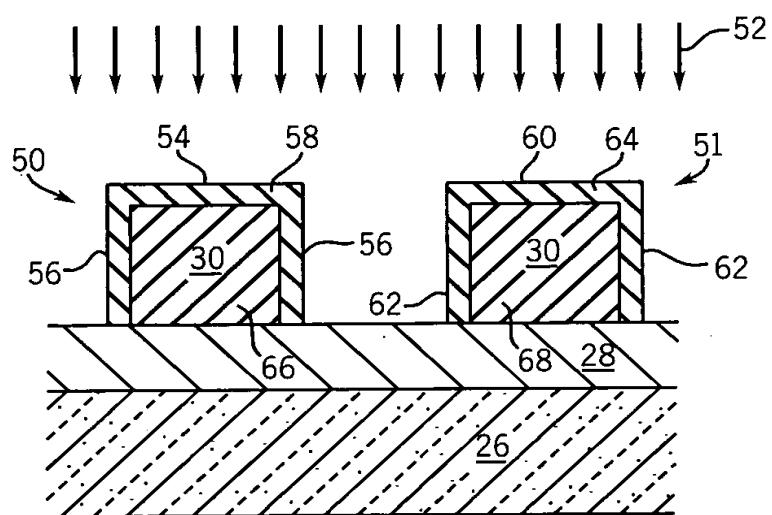


FIG. 4



4 / 4

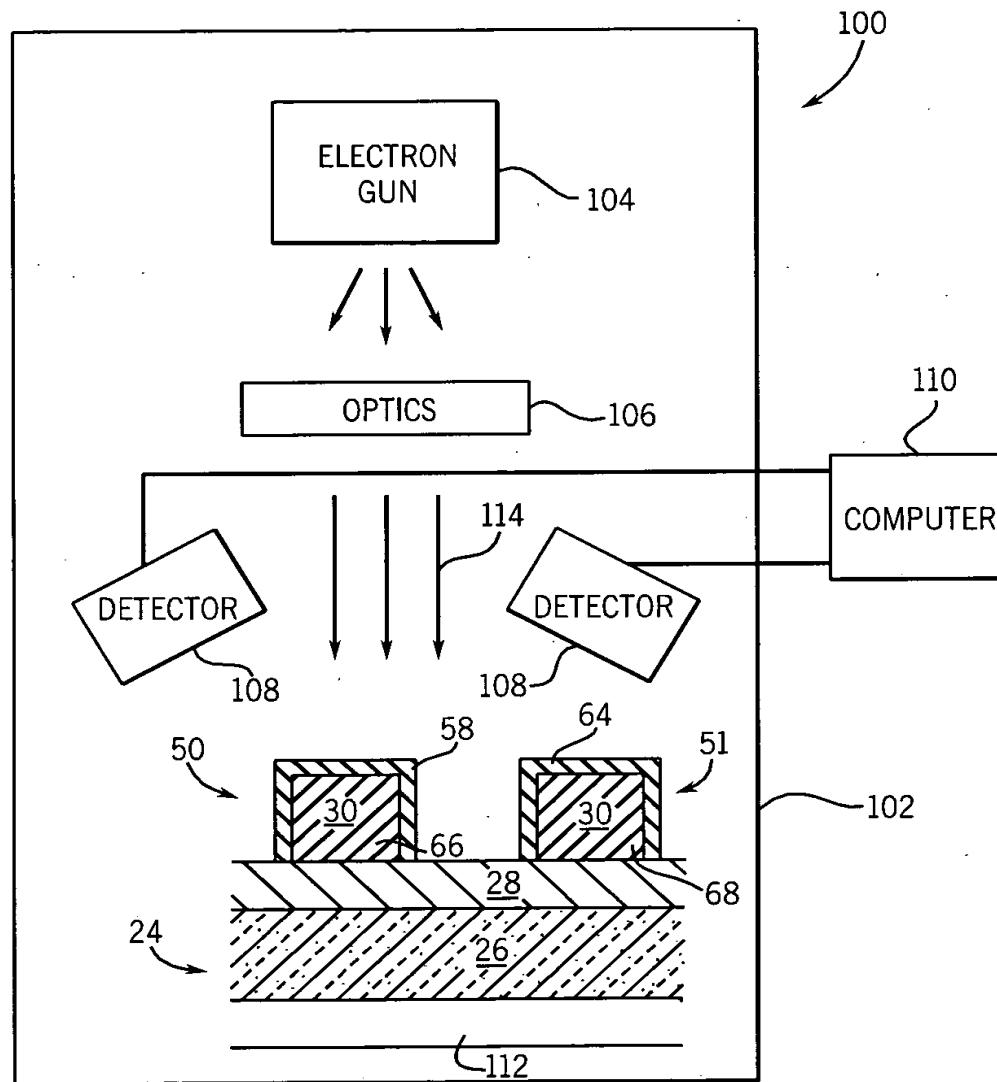


FIG. 5